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2/25/05

Substitute for form 1449A/B/PTO				Complete if Known	
				Application Number	Not Yet Assigned
				Filing Date	Concurrently Herewith
				First Named Inventor	Etsuo Kawate
				Art Unit	N/A
				Examiner Name	Not Yet Assigned
Sheet	1	of	1	Attorney Docket Number	AIS-0014

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number	Publication Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (if known)	MM-DD-YYYY		
NS	AA	20040008346-A1	01-15-2004	Kawate	

FOREIGN PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)	DD-MM-YYYY		
AS	BA	JP-62-132152-A1	06-15-1987	Hitachi Ltd.	
AS	BB	JP-64-035306-A1	02-06-1989	Ricoh Co., Ltd.	
AS	BC	JP-2002-296111-A1	10-09-2002	National Institute of Advanced Industrial & Technology	

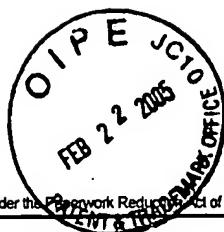
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NON PATENT LITERATURE DOCUMENTS					
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.			T ²
NS	CA	L. Ward, et al. "A theoretical study of the sensitivities of some normal incidence methods for measuring the optical constants and thicknesses of thin films" BRIT. J. APPL. PHYS., Vol. 18, pp. 277 - 284, (1967)			
AS	CB	J. E. Nestell, Jr., et al. "Derivation of Optical Constants of Metals from Thin-Film Measurements at Oblique Incidence", Applied Optics, Vol. 11, No. 3, pp. 643-651, (03/1972)			
NS	CC	Leonard Hanssen et al. "Methods for absolute reflectance measurement of transmissive materials in the infrared" SPIE, Vol. 3425, pp. 16 - 27, (07/1998)			
AS	CD	Etsuo Kawate "Symmetry X system and method for absolute measurements of reflectance and transmittance of specular samples" APPLIED OPTICS, Vol. 42, No. 25, pp. 5064 - 5072 (09/2003)			

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Examiner Signature	M. Kawate / Staff	Date Considered	11-4-05
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PTO/SB/08a/b (08-03)

Approved for use through 07/31/2006. OMB 0651-0031
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Substitute for form 1449A/B/PTO				Complete If Known	
				Application Number	10/785,055-Conf. #8560
				Filing Date	February 25, 2004
				First Named Inventor	Etsuo Kawate
				Art Unit	2877
				Examiner Name	Not Yet Assigned
Sheet	1	of	1	Attorney Docket Number	AIS-0014

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FOREIGN PATENT DOCUMENTS					
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		Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)			
MF	BA	JP-11-183320-A	07-09-1999	Nikon Corp.	
MF	BB	JP-2000-180351-A	06-30-2000	Nikon Corp.	
MF	BC	JP-2002-296111-A	10-09-2002	National Institute of Advanced Industrial & Technology	

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MF	CA	Japanese Office Action dated December 12, 2004			

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Examiner Signature	Michael Stahl	Date Considered	11-41-05
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